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TEST REPORT

Application No:	GZEM1307003394HS			
Applicant:	Dongguan Richtek Electronics Co., Ltd.			
Product Name:	Air Compressor			
Product Description:	Air Compressor			
Model No:	RCP-A24C, RCP-A24B, RCP-A24D, RCP-A24E, RCP-D070, RCP-D12B, RCP-B160, RCP-D01, RCP-D02, RCP-D08B, RCP-D10A, RCP-D13B, RCP-C43B, RCP-B28A, RCP-B28B, RCP-B28C, RCP-B49A, RCP-B49B .			
*	Please refer to section 3 of this report for further details.			
Standards:	EN 50498:2010 (as per applicant's request)			
Date of Receipt:	2013-07-25			
Date of Test:	2013-07-30 to 2013-08-02			
Date of Issue:	2013-08-29			
Test Result :	Pass*			

* In the configuration tested, the EUT complied with the standards specified above.

The CE mark as shown below can be used, under the responsibility of the manufacturer, after completion of an EC Declaration of Conformity and compliance with all relevant EC Directives.



Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards.

The report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the federal government. All test results in this report can be traceable to National or International Standards.

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2 Version

Revision Record						
Version	Chapter	Date	Modifier	Remark		
00		2013-08-29		Original		

Authorized for issue by:		
Tested By	(Evan Huang) /Project Engineer	2013-07-30 to 2013-08-02 Date
Prepared By	Millie Li) /Clerk	2013-08-27 Date
Checked By	Curican Mueng	2013-08-29
	(Guitar Huang) /Reviewer	Date



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3 Test Summary

Electromagnetic Interference (EMI)						
Test	Test Requirement	Test Method	Class / Severity	Result		
Radiated Emissions (30 MHz to 1 GHz)	EN 50498:2010	2004/104/EC Clause 6.5 and 6.6	Table 1 for broad band Table 2 for narrow band	PASS		
Transient Conducted Emissions	EN 50498:2010	2004/104/EC & ISO 7637-2:2004	Table 3	PASS		
Electromagnetic Suscep	tibility (EMS)					
Test	Test Requirement	Test Method	Class / Severity	Result		
Transient Conducted Immunity	EN 50498:2010	2004/104/EC & ISO 7637-2:2004	Table 4	PASS		

[♣] Model No.: RCP-A24C, RCP-A24B, RCP-A24D, RCP-A24E, RCP-D070, RCP-D12B, RCP-B160, RCP-D01, RCP-D02, RCP-D08B, RCP-D10A, RCP-D13B, RCP-C43B, RCP-B28A, RCP-B28B, RCP-B28C, RCP-B49A, RCP-B49B

According to the declaration from the applicant, the electrical circuit design, layout, components used and internal wiring were identical for all models, with only difference being the outer decoration and model name. Therefore only one model **RCP-A24C** was tested in this report.



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5 General Information

5.1 Client Information

Applicant: Dongguan Richtek Electronics Co., Ltd.

Address of Applicant: No.11, Kuiging Road, Qingxi Town, Dongguan City, China

5.2 General Description of E.U.T.

Product Name: Air Compressor

Product Description: Air Compressor

Model No: RCP-A24C

5.3 Details of E.U.T.

Rated Supply (Voltage): DC 12V

Power Cable: 3.5m x 2 wires unscreened DC mains cable.

5.4 Description of Support Units

The EUT has been tested with DC 12V battery.

5.5 Deviation from Standards

None.

5.6 General Test Climate During Testing

Temperature: 15-30 °C Humidity: 30-70 %RH Atmospheric Pressure: 860-1060 mbar

5.7 Abnormalities from Standard Conditions

None.

5.8 Monitoring of EUT for All Immunity Test

Audio: N/A

Visual: LED and Pressure meter

5.9 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd., Guangzhou EMC Laboratory,

198 Kezhu Road, Scientech Park, Guangzhou Economic & Technology Development District,

Guangzhou, China 510663

Tel: +86 20 82155555 Fax: +86 20 82075059

No tests were sub-contracted.



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5.10 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

NVLAP (Lab Code: 200611-0)

SGS-CSTC Standards Technical Services Co., Ltd., Guangzhou EMC Laboratory is recognized under the National Voluntary Laboratory Accreditation Program (NVLAP/NIST). NVLAP Code: 200611-0.

ACM A

SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory can also perform testing for the Australian C-Tick mark as a result of our NVLAP accreditation.

• SGS UK(Certificate No.: 32), SGS-TUV SAARLAND and SGS-FIMKO

Have approved SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory as a supplier of EMC TESTING SERVICES and SAFETY TESTING SERVICES.

CNAS (Lab Code: L0167)

SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory has been assessed and in compliance with CNAS-CL01:2006 accreditation criteria for testing laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of Testing Laboratories.

• FCC (Registration No.: 282399)

SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 282399, May 31, 2002.

Industry Canada (Registration No.: 4620B-1)

The 3m/10m Alternate Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. has been registered by Certification and Engineering of Industry Canada for radio equipment testing with Registration No. 4620B-1.

VCCI (Registration No.: R-2460, C-2584, G-449 and T-1179)

The 10m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-2460, C-2584, G-449 and T-1179 respectively.

• CBTL (Lab Code: TL129)

SGS-CSTC Standards Technical Services Co., Ltd., E&E Laboratory has been assessed and fully comply with the requirements of ISO/IEC 17025:2005, the Basic Rules, IECEE 01:2006-10 and Rules of procedure IECEE 02:2006-10, and the relevant IECEE CB-Scheme Operational documents.



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6 Equipment Used during Test

RE in Cha	RE in Chamber (for automotive)						
No.	Test Equipment	Manufacturer	Model No.	Serial No.	Cal.Due date (YYYY-MM-DD)	Calibratio n Interval	
EMC0525	Compact Semi- Anechoic Chamber	ChangZhou ZhongYu	N/A	N/A	2014-08-30	2Y	
EMC0522	EMI Test Receiver	Rohde & Schwarz	ESIB26	100283	2014-05-06	1Y	
N/A	EMI Test Software	Audix	E3	N/A	N/A	N/A	
EMC0514	Coaxial cable	SGS	N/A	N/A	2013-12-28	2Y	
EMC0524	Bi-log Type Antenna	Schaffner -Chase	CBL6112B	2966	2013-11-27	2Y	
EMC2065	Amplifier	HP	8447F	N/A	2013-11-07	1Y	
EMC1801	Artifical Mains Network	Schwarzbeck	NNBM 8125	81251342	2014-03-04	1Y	
EMC1802	Artifical Mains Network	Schwarzbeck	NNBM 8125	81251345	2014-03-04	1Y	

ISO7637-	ISO7637-2 Transient Conducted Emissions						
No.	Test Equipment	Manufacturer	Model No.	Serial No.	Cal.Due date	Calibratio	
140.	rest Equipment	Manufacturei	Model No.	Serial No.	(YYYY-MM-DD)	n Interval	
EMC1801	Artifical Mains Network	Schwarzbeck	NNBM 8125	81251342	2014/3/4	1Y	
EMC1802	Artifical Mains Network	Schwarzbeck	NNBM 8125	81251345	2014/3/4	1Y	
EMC1803	Electronic Switch	EM Test/AG	BS200B	V0725102620	2013/10/5	1Y	
EMC2012	digitizing oscilloscope	Tektronix	TDS744A	N/A	2014/3/4	1Y	

ISO7637-	ISO7637-2 Transient Conducted Immunity						
No.	Test Equipment	Manufacturer	Model No.	Serial No.	Cal.Due date (YYYY-MM-DD)	Calibratio n Interval	
EMC1804	Ultra Compact Simulator	EM Test/AG	UCS 200M	V0725102618	2013-11-5	1Y	
EMC1805	Voltage Drop Generator	EM Test/AG	VDS 200 B2	V0725102619	2013-11-5	1Y	

General u	General used equipment						
No.	Test Equipment	Manufacturer	Model No.	Serial No.	Cal.Due date (YYYY-MM-DD)		
EMC0006	DMM	Fluke	73	70681569	2013-11-5	1Y	
EMC0007	DMM	Fluke	73	70671122	2013-11-5	1Y	



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7 EMI and EMS Test Results (EN50498)

7.1 Radiated Emissions, 30 MHz to 1 GHz

Test Requirement: EN 50498

Test Method: Clause 6.5 and 6.6 of 2004/104/EC

Test Date: 2013-07-30
Test Voltage: DC 13.5V

Frequency Range: 30 MHz to 1 GHz

Measurement Distance: 1 meter

Limits: Table 1 of EN 50498 (for broadband emissions)

Frequency range F	Limits Quasi peak
MHz	dBμV/m
30 to 75	62 – 52 ^a
75 to 400	52 – 63 ^b
400 to 1 000	63

a Decreasing linearly with the log of the frequency.

Table 2 of EN 50498 (for narrowband emissions)

Limits Average
dBμV/m
52 – 42 ^a
42 – 53 ^b
53

a Decreasing linearly with the log of the frequency.

Detector: Peak for pre-scan (120 kHz resolution bandwidth)

Quasi-Peak for broadband emissions Average for narrowband emissions

7.1.1 E.U.T. Operation

EUT Operation: Test the EUT in motor running mode.

Before test, the voltage of the vehicle battery is 13.5V. After test, the voltage of the vehicle battery is 13.2V.

Increasing linearly with the log of the frequency.

Increasing linearly with the log of the frequency.

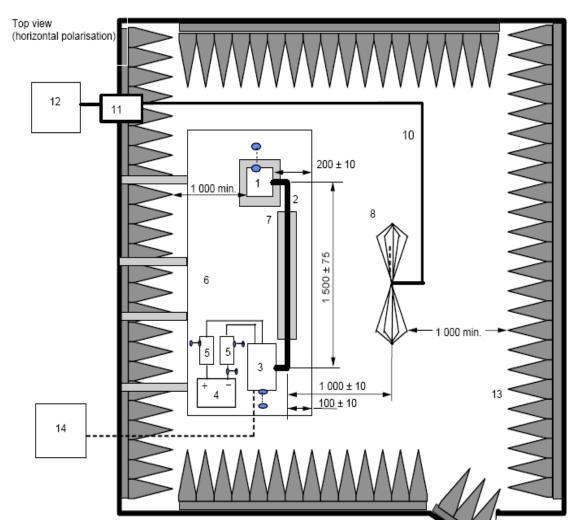


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7.1.2 Test Setup and Procedure

The EUT was insulated placed 50 mm above the ground plane, the ground plan was in a height of 1 m to the reference plane of semi-anechoic chamber and with electrical connection. No additional electric connection was made between the EUT and ground plane as the EUT will not be intended to be bonded to the bodywork of the vehicle. The EUT was powered by 12 V vehicle battery through 5 uH/50 ohm LISN.



Key

EUT (grounded locally if required in test plan)	8. Antenna
2. Test harness	10. High-quality coaxial cable
3. Load simulator	11. Bulkhead connector
4. Power supply (location optional)	12. Measuring instrument
5. Artificial network (AN)	13. RF absorber material
6. Ground plane (bonded to shielded enclosure)	14. Stimulation and monitoring system
7. Low relative permittivity support	

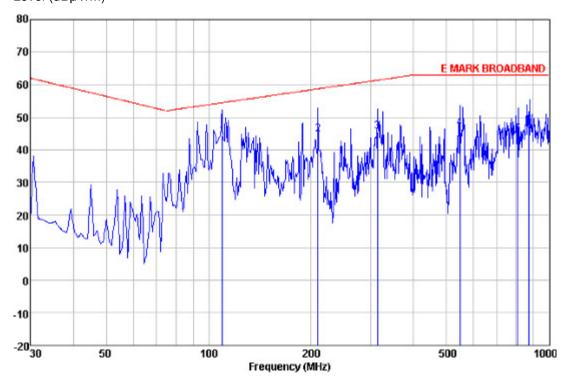


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7.1.3 Measurement Data

Polarisation: Horizontal: Peak scan Level (dBµV/m)



QP measurement for Broadband emissions.

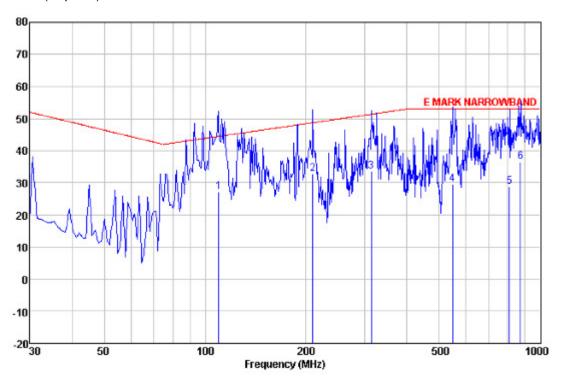
Fr	eq		Antenna Factor					Over Limit	Remark
м	Hz	dBuV	dB/m	dB	dB	dBuV/m	dBuV/m	dB	
109.5 209.4		58.76 61.09		0.24 0.74		44.30 44.84		-10.19 -13.91	-
313.2	40	57.14	13.30	1.03	25.86	45.61	61.39	-15.78	QР
547.0 808.9		53.91 49.78	18.47 20.20	1.44 1.75	27.21 27.03	46.61 44.70		-16.39 -18.30	_
873.9	00	51.68	20.75	1.99	26.84	47.58	63.00	-15.42	OP



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Horizontal Peak scan Level (dBµV/m)



Average measurement for Narrowband emissions.

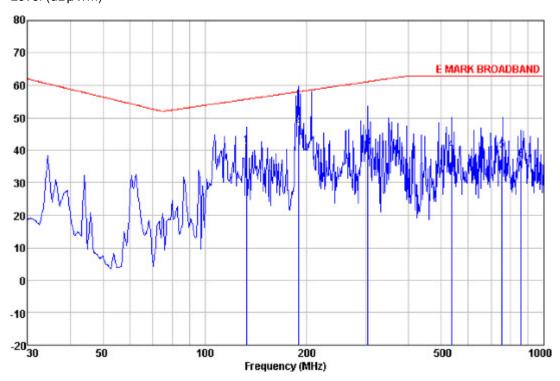
Freq		Antenna Factor				Limit Line	Over Limit	Remark
MHz	dBuV	dB/m	dB	dB	dBuV/m	dBuV/m	dB	
109.540	41.76	11.86	0.24	26.56	27.30	44.49	-17.19	Average
209.450	49.09	9.09	0.74	26.08	32.84	48.75	-15.91	Average
313.240	45.14	13.30	1.03	25.86	33.61	51.39	-17.78	Average
547.010	36.91	18.47	1.44	27.21	29.61	53.00	-23.39	Average
808.910	33.78	20.20	1.75	27.03	28.70	53.00	-24.30	Average
873.900	40.68	20.75	1.99	26.84	36.58	53.00	-16.42	Average



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Polarisation: Vertical: Peak scan Level (dBµV/m)



QP measurement for Broadband emissions.

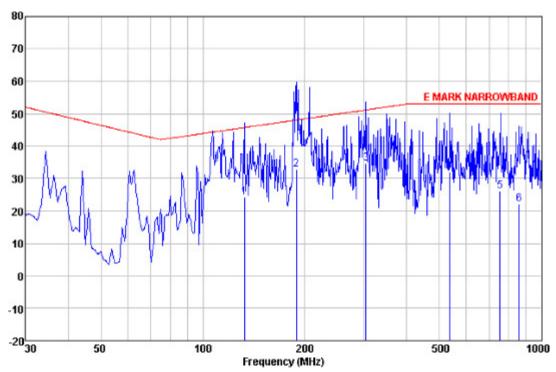
Freq		ntenna Factor					Over Limit	Remark
MHz	dBuV	dB/m	dB	dB	dBuV/m	dBuV/m	dB	
132.820	55.44	11.84	0.41	26.43	41.26	55.76	-14.50	QP
189.080	64.75	8.39	0.70	26.13	47.71	58.08	-10.37	QP
303.540	52.74	12.80	1.00	25.83	40.71	61.19	-20.48	QP
534.400	47.68	18.02	1.47	27.17	40.00	63.00	-23.00	QP
753.620	45.04	20.25	1.84	27.09	40.04	63.00	-22.96	QP
856.440	41.48	20.50	2.04	26.89	37.13	63.00	-25.87	QP



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Vertical: Peak scan Level (dBµV/m)



Average measurement for Narrowband emissions.

Freq		Antenna Factor				Limit Line	Over Limit	Remark
MHz	dBuV	dB/m	dB	dB	dBuV/m	dBuV/m	dB	
132.820	38.44	11.84	0.41	26.43	24.26	45.76	-21.50	Average
189.080	49.75	8.39	0.70	26.13	32.71	48.08	-15.37	Average
303.540	46.74	12.80	1.00	25.83	34.71	51.19	-16.48	Average
534.400	39.68	18.02	1.47	27.17	32.00	53.00	-21.00	Average
753.620	31.04	20.25	1.84	27.09	26.04	53.00	-26.96	Average
856.440	26.48	20.50	2.04	26.89	22.13	53.00	-30.87	Average



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7.2 Transient Conducted Emissions Test

Test Requirement: EN 50498

Test Method: Clause 6.9 of 2004/104/EC & ISO 7637-2

Test Date: 2013-08-02
Test Voltage: DC 13.5V

Test Limit: Table 3 of EN50498

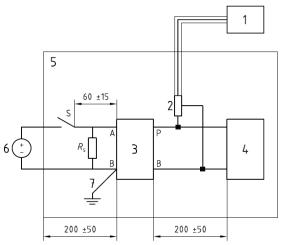
Table 3 - Limits of transient disturbances

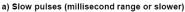
Polarity of pulse amplitude	Maximum allowed	pulse amplitude for
	vehicles with 12 V systems	vehicles with 24 V systems
Positive	+ 75	+ 150
Negative	- 100	- 450

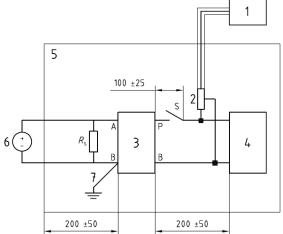
7.2.1 E.U.T. Operation

EUT Operation: Test the EUT in motor running mode.

7.2.2 Test Setup







b) Fast pulses (nanosecond-to-microsecond range)

Key	
1. oscilloscope	5. ground plane
2. voltage probe	6. power supply
3. artificial network	7. Ground connection; length < 100 mm
4. EUT(source of transient)	



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7.2.3 Measurement Data

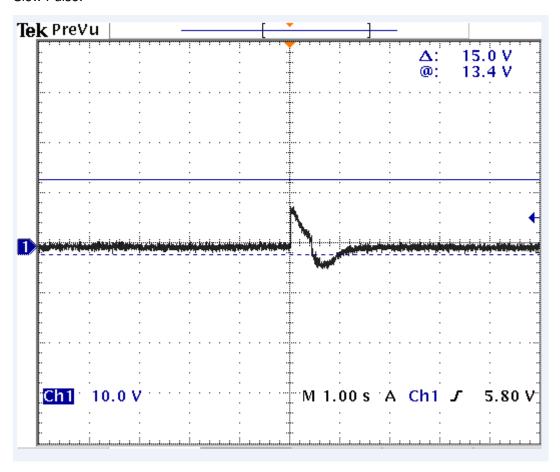
12V systems:

Polarity of pulse amplitude	Maximum allowed pulse amplitude(V)	Type of pulse	Observation result (V)
Dogitivo	. 76	Slow	8.4
Positive	+75	Fast	8.6
Magativa	100	Slow	2.7
Negative	-100	Fast	4.7

The Worst case Voltage Waveforms:

12 V systems:

Slow Pulse:

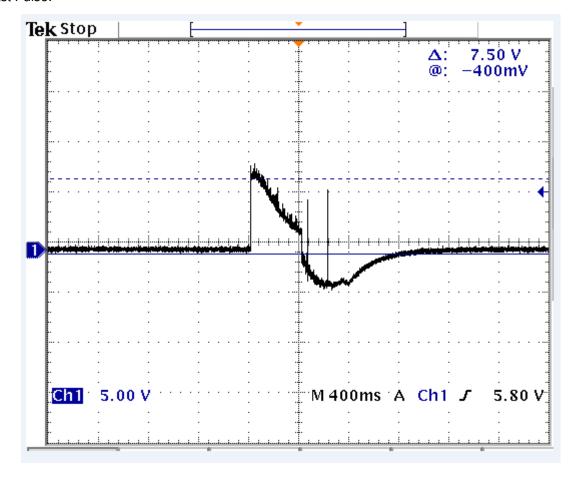




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Fast Pulse:





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Performance Criteria Description in A.4 of ISO 7637-2

Criterion A:

all functions of a device/system perform as designed during and after exposure to disturbance.

Criterion B:

all functions of a device/system perform as designed during exposure. However, one or more of them can go beyond specified tolerance. All functions return automatically to within normal limits after exposure is removed. Memory functions shall remain class A.

Criterion C:

one or more functions of a device/system do not perform as designed during exposure but return automatically to normal operation after exposure is removed.

Criterion D:

one or more functions of a device/system do not perform as designed during exposure and do not return to normal operation until exposure is removed and the device/system is reset by simple "operator/use" action.

Criterion E:

one or more functions of a device/system do not perform as designed during and after exposure and cannot be returned to proper operation without repairing or replacing the device/system.



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7.3 Transient Conducted Immunity

Test Requirement: EN 50498

Test Method: Clause 6.8 2004/104/EC & ISO 7637-2

 Test Date:
 2013-08-02

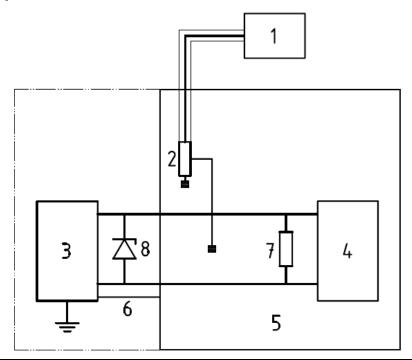
 Test Voltage:
 DC 13.5V

Test Limit: Table 4 of EN50498

7.3.1 E.U.T. Operation

EUT Operation: Test the EUT in motor running mode.

7.3.2 Test Setup



Key	
1. oscilloscope	5. ground plane
2. voltage probe	6. Ground connection
3. test pulse generator with internal power	7. optional resistor (<i>R</i> v) ^a
supply resistance <i>R</i> i	
4. EUT	8. optional diode bridge ^b

a For simulation of vehicle system loading for load dump test pulses 5a and 5b only. If used, the value of Rv shall be specified in the test plan (typical value 0,7 Ω to 40 Ω).

b For simulation of load dump waveform for alternator with centralized load dump suppression for pulse 5b only



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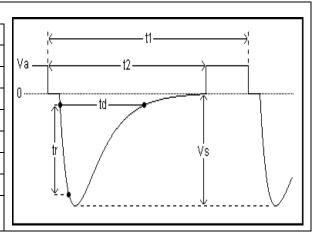
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7.3.3Measurement Data

Pulse 1

12V

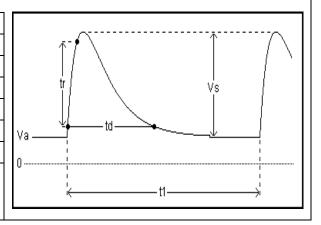
Vs:	-75	٧
t1:	0.5	s
t2:	200	ms
tr:	1	us
td:	2000	us
Ri:	10	Ohm
Coupling:	Battery	
Events:	5000	
Test duration:	00:41:40	h



Pulse 2a

12V

Vs:	+37	٧
t1:	0.2	s
tr:	1	us
td:	50	us
Ri:	2	Ohm
Coupling:	Battery	
Events:	5000	
Test duration:	00:16:40	h





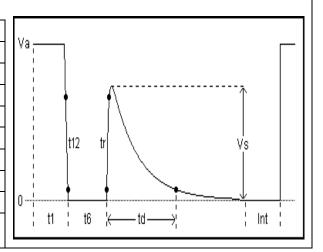
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Pulse 2b

12V

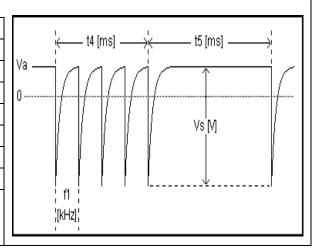
Vs:	10.0	V
t1:	1.0	S
t6:	1	ms
td:	200	ms
Int:	1.0	S
Ri:	0.05	Ohm
t12:	1	ms
tr:	1	ms
Events:	10	
Test duration:	00:00:28	h



Pulse 3a

12V

Vs:	-112	٧
f1:	10	kHz
t4:	10	ms
t5:	90	ms
tr:	5	ns
td:	100	ns
Ri:	50	Ohm
Coupling:	Battery	
Test duration:	1	h





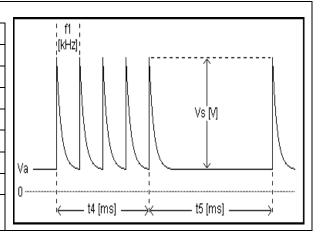
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Pulse 3b

12V

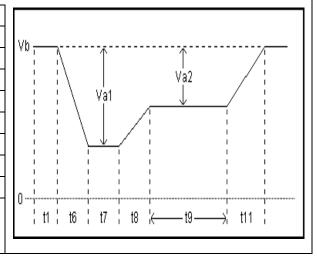
Vs:	+75	V
f1:	10	kHz
t4:	10	ms
t5:	90	ms
tr:	5	ns
td:	100	ns
Ri:	50	Ohm
Coupling:	Battery	
Test duration:	1	h



Pulse 4

12V

Va1:	-6.0	V
Va2:	-2.5	V
t1:	1.0	S
t6:	5	ms
t7:	15	ms
t8:	50	ms
t9:	0.5	S
t11:	5	ms
Events:	1	
Test duration:	00:00:02	h





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Test Results:

Test Pulse Number	Immunity Test Level for 12V (min. voltage)	Performance Criterion required not immunity- related	Performance under test
		not ininianity Tolatou	
1	III (-75)	D	(B)
2 a	III (+37)	D	(A)
2 b	III (+10)	D	(B)
3 a	III (-112)	D	(A)
3 b	III (+75)	D	(B)
4	III (-6)	D	(B)

Remark:

EUT is not immunity- related product.

(A): No Loss of Function.

(B): During test, the EUT speed slowed, and it could recover automatically after test.

Conclusion:

The EUT can meet the requirements of the standard.

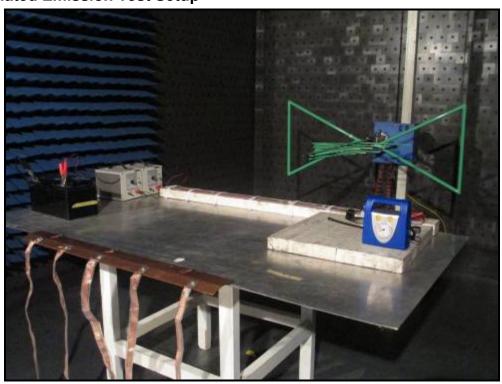


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8 Photographs

8.1 Radiated Emission Test Setup



8.2 Transient Conducted Emissions Test Setup







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For fast Pulse:



8.3 Transient Conducted Immunity Test Setup





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8.4 EUT Constructional Details



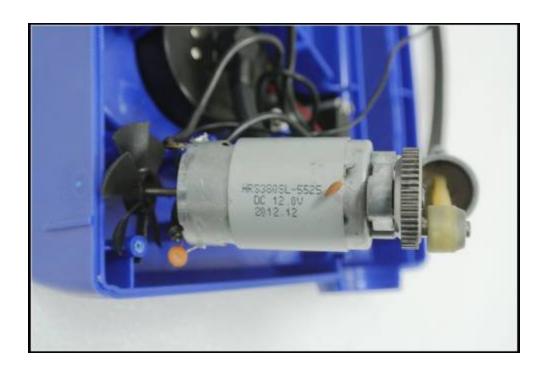




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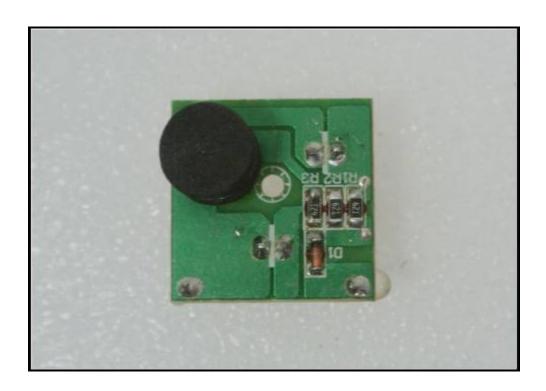


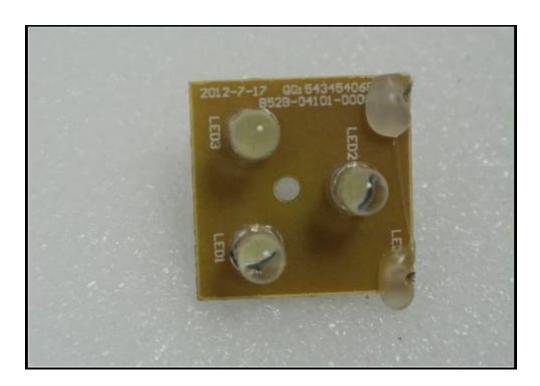




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